



General Description

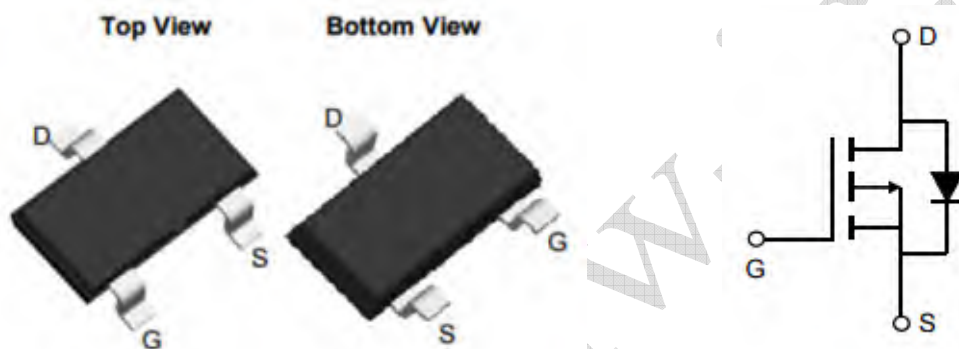
These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments
- USB cable

Product Summary

- V_{DS} -30V
- I_D (at $V_{GS} = 10V$) -5.1A
- $R_{DS(ON)}$ (at $V_{GS} = -10V$) < 32m Ω
- $R_{DS(ON)}$ (at $V_{GS} = -4.5V$) < 46m Ω



Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	-5.1	A
		-3.2	
Pulsed Drain Current ^A	I_{DM}	-20	A
Power Dissipation	P_D	1.56	W
		0.9	
Storage Temperature Range	T_{STG}	-55 to +150	$^\circ\text{C}$
Operating Junction Temperature Range	T_J	-55 to +150	$^\circ\text{C}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	80	$^\circ\text{C/W}$

**Electrical Characteristics (T_J=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250uA, V _{GS} =0V	-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-30V, V _{GS} =0V			1	uA
I _{GSS}	Gate-Bodyleakagecurrent	V _{DS} =0V, V _{GS} =±20V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250uA	-1.2	-1.6	-2.2	V
I _{D(ON)}	Onstate draincurrent	V _{GS} =10V, V _{DS} =5V	-20			A
R _{DS(ON)}	StaticDrain-Source On-Resistance	V _{GS} =-10V, I _D =-4A		27	32	mΩ
		V _{GS} =-4.5V, I _D =-2A		38	46	mΩ
g _{FS}	ForwardTransconductance	V _{DS} =-5V, I _D =-4.1A		9		S
V _{SD}	Diode Forward Voltage	I _{DS} =-1A, V _{GS} =0V		-0.7	-1	V
I _S	Maximum Body-Diode ContinuousCurrent				-5.1	A
DYNAMIC PARAMETERS						
C _{iss}	InputCapacitance	V _{GS} =0V, V _{DS} =-15V, f=1MHz		760	1280	pF
C _{oss}	OutputCapacitance			122	210	pF
C _{rss}	Reverse TransferCapacitance			88	175	pF
SWITCHING PARAMETERS						
Q _g	TotalGate Charge ^{2,3}	V _{GS} =-4.5V, V _{DS} =-15V, I _D =-5A		8	15	nC
Q _{gs}	Gate Source Charge ^{2,3}			3.3	6	nC
Q _{gd}	Gate Drain Charge ^{2,3}			2.3	5	nC
t _{D(on)}	Turn-OnDelayTime ^{2,3}	V _{GS} =-10V, V _{DS} =-15V, R _G =6Ω, I _D =-1A		4.6	9	ns
t _r	Turn-On Rise Time ^{2,3}			14	26	ns
t _{D(off)}	Turn-OffDelayTime ^{2,3}			34	58	ns
t _f	Turn-OffFallTime ^{2,3}			18	35	ns

Notes:

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
3. Essentially independent of operating temperature.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

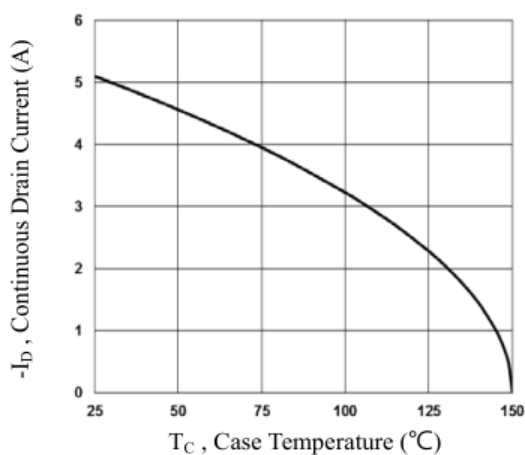


Fig 1: Continuous Drain Current vs. T_c

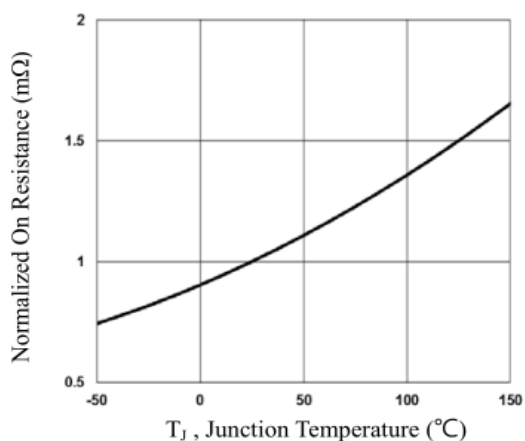


Fig.2 Normalized RDSON vs. T_j

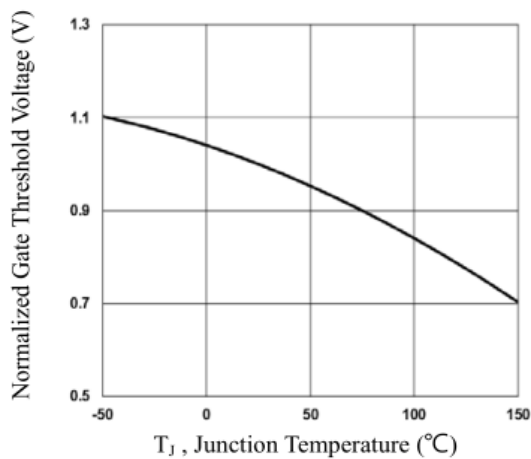


Figure 3: Normalized V_{th} vs. T_j

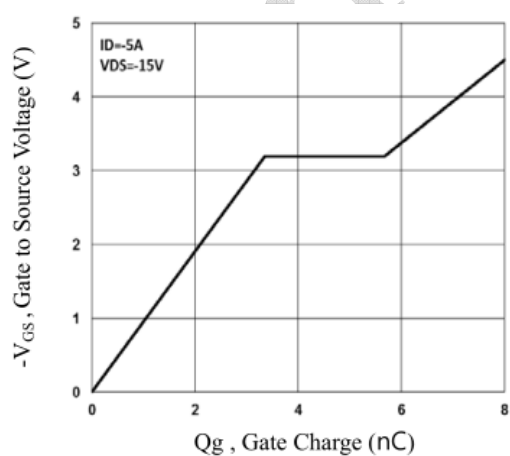


Figure 4: Gate Charge Waveform

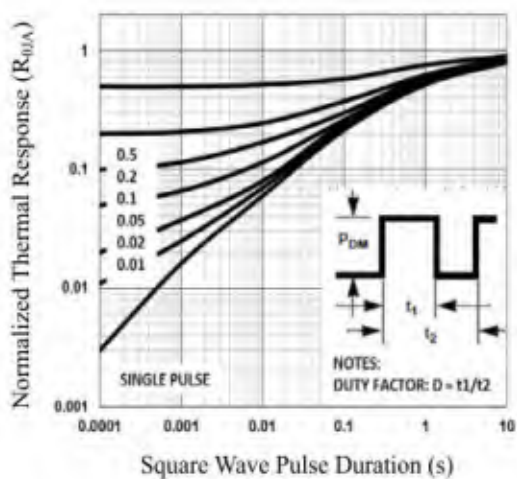


Figure 5: Normalized Transient Impedance

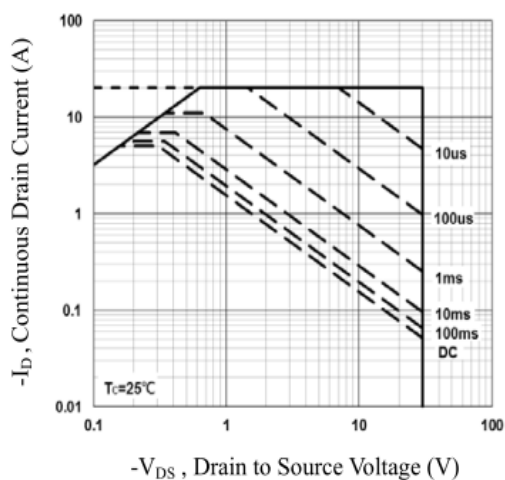


Figure 6: Maximum Safe Operation Area

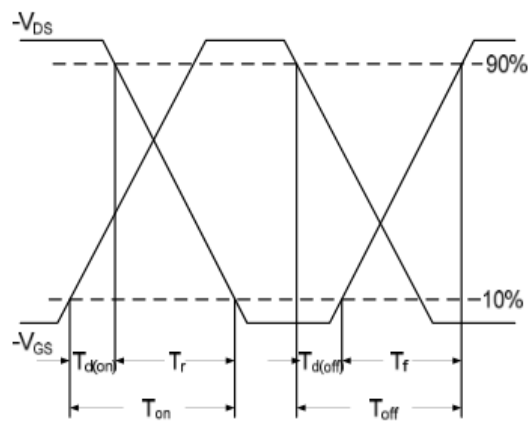


Figure 7: Switching Time Waveform

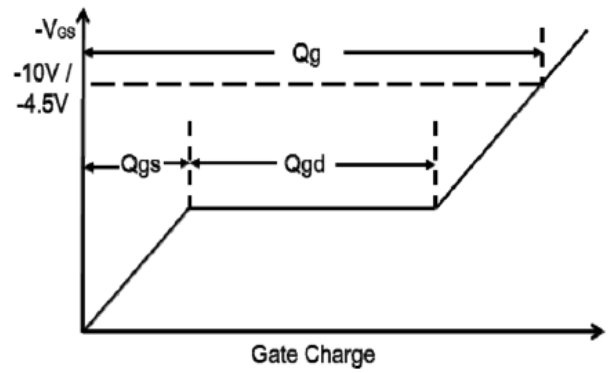
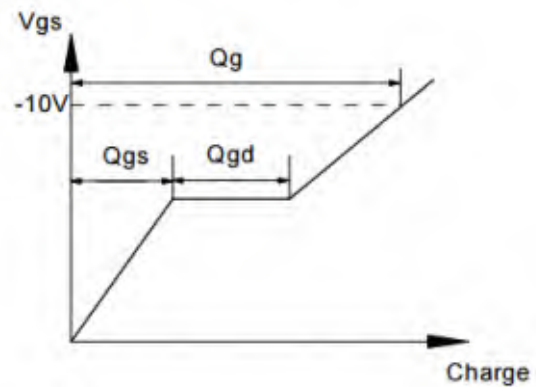
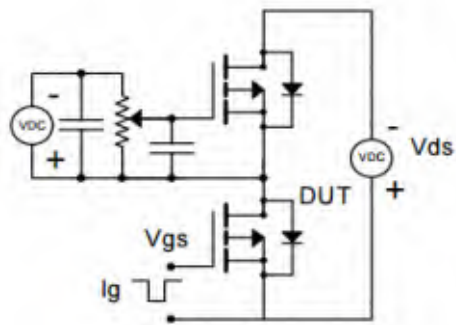


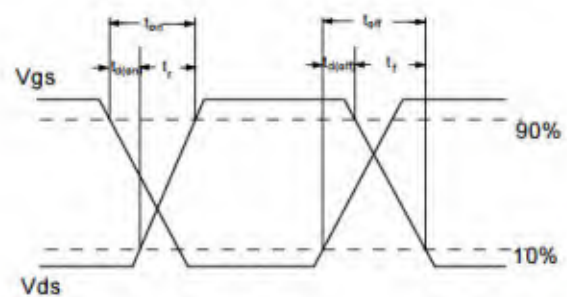
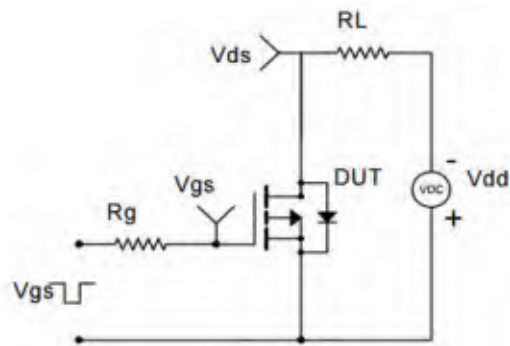
Figure 8: Gate Charge Waveform



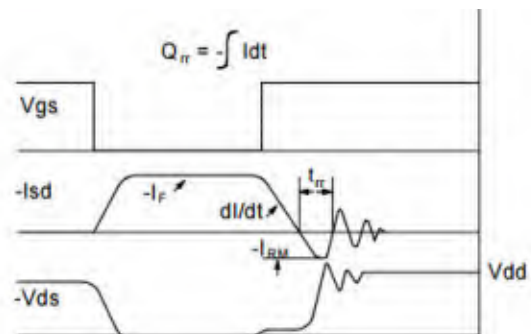
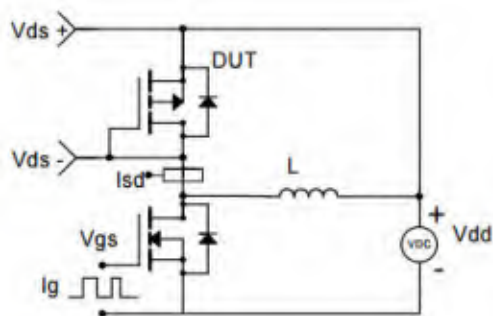
Gate Charge Test Circuit & Waveform

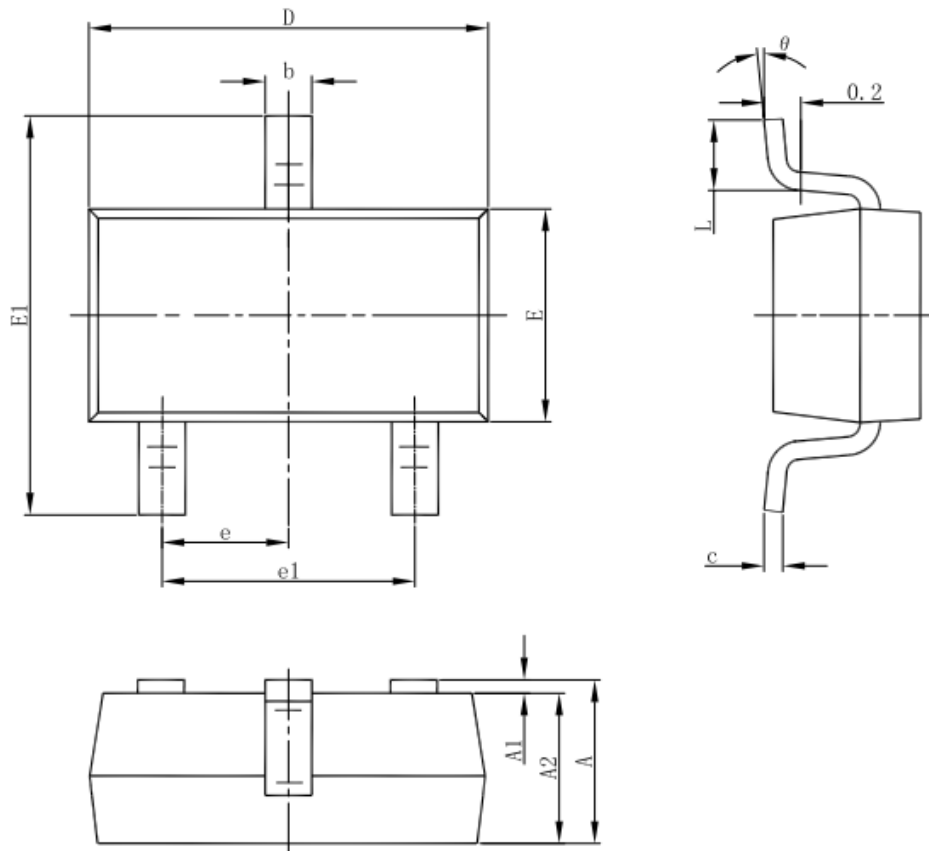


Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



**Package Information****SOT23-3L**

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
c	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E	1.500	1.700	0.059	0.067
E1	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.037(BSC)	
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°